



ISTITUTO ITALIANO  
DI TECNOLOGIA

## TITLE

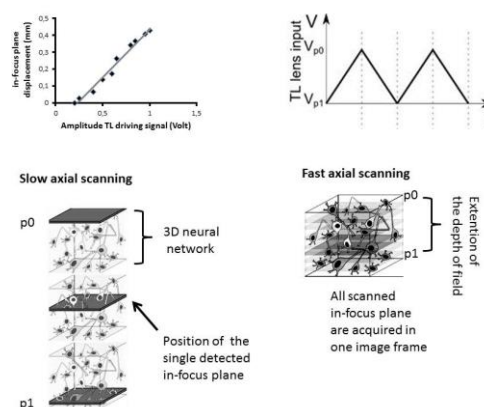
Metodo di analisi di informazioni spaziali e temporali di campioni mediante microscopia ottica

## INVENTORS

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## DESCRIPTION

The invention relates to a method for a specific architecture of optical microscope, which provide an inertia-free axial scanning of the sample, which could be used to acquire a z-stack of the sample or to extend the depth of field of the microscope. The extension of the depth of field can be arbitrarily chosen by controlling the extension of the fast axial scanning of the sample.



## APPLICATIONS

Extended depth field microscopy

## KEYWORDS

Dynamic Phase modulation, inertia-free axial scanning, tunable extension of the depth of field

## BIBLIOGRAPHIC DATA

Method for the analysis of spatial and temporal information of samples using light microscopy

Application Number

IT 102016000097811

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Applicants

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